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Application/Control No.	Applicant(s)/Patent under Reexamination
10/751,414	SHIRAI ET AL.
Examiner [*]	Art Unit
Ryan D. Walsh	2852

	SEARCHED				
Class	Subclass	Date	Examiner		
399	86	8/3/2005	RDW		
399	197	8/3/2005	RDW		
399	196	8/3/2005	RDW		
382	170	8/3/2005	RDW		
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
IDS	8/3/2005	RDW	
East: See attached	8/3/2005	RDW	
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